WEST Search History

| Hide Items | Restore | Clear | Cancel |

DATE: Monday, December 29, 2003

Hide?	Set Name	Query	Hit Count
		DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ	
☐	L13	('20030029647' |'20030029648' |'6595306')!.PN.	5
☐	L12	18 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array)and (test$3 or detect$3 or debug$4)	3
☐	L11	18 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array) same (test$3 or detect$3 or debug$4)	0
☐	L10	18 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array) same (test$3 or detect$3 or debug$4)	0
☐	L9	18 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array) same (test$3 or detect$3 or debug$4)	0
☐	L8	fork$3 with walk$3	298
☐	L7	fork$3 with walk$3	298
☐	L6	11 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array)	14
☐	L5	11 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array)	14
☐	L4	11 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array)	14
☐	L3	11 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array)	14
☐	L2	fork$3 with walk$3	298
☐	L1	fork$3 with walk$3	298

END OF SEARCH HISTORY

IEEE HOME : SEARCH IEEE : SHOP : WEB ACCOUNT : CONTACT IEEE   ◈IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE *Xplore*
RELEASE 1.6
                                                    Welcome
                                    United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links   [▼]   » Search Results
Peer Review

Welcome to IEEE Xplore

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account
○ Access the
   IEEE Member
   Digital Library

Your search matched **0** of **19** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by
Relevance in **Descending** order.

Refine This Search:
You may refine your search by editing the current search
expression or entering a new one in the text box.

[   ]

[Search]

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account
| New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE
Online Publications | Help | FAQ | Terms | Back to Top